

**Search Notes**

Application/Control No.

10/647,784

Examiner

D. Rutledge

Applicant(s)/Patent under  
Reexamination

KURT ET AL.

Art Unit

2851

**SEARCHED**

Class	Subclass	Date	Examiner
355	53,67,71	3/19/2005	DR
378	84	3/19/2005	DR
359	350,361	3/19/2005	DR
428	141,408	3/19/2005	DR
428	450, 469	3/19/2005	DR
427	162,402	3/19/2005	DR
427	595	3/19/2005	DR
250	505.1	3/19/2005	DR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
355	67,53,71	3/19/2005	DR
359	350,361	3/19/2005	DR
387	84	3/19/2005	DR
428	141,408,450,469		
427	162,402,595		
250	505.1		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
lithograph\$3 or exposure or projection; optic\$3 or mirror; rust or oxidation; multilayer; si or silicon; mo or molybdenum;	3/19/2005	DR
cap\$4 or top; layer; (7 or 7.2 or 7.5 or 8 or 9) adj nm; c or carbon or 'si/mo'	3/19/2005	DR